

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number						
		BZX8850S-C2V7-Q						
		Part Description						
		Nexperia DHAM Zener						
		MCD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113						
		Bake Tamb = 125 °C	24 hours					
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours					
# A1	Preconditioning	Reflow soldering	3 cycles	212	9600	0		
		MIL-STD-750-1						
	HTRB	M1038 Method A						
		Tj = Tjmax, VR = 80 % of rated reverse						
# B1	Bias	voltage	1000 hours	250	11400	0		
		MIL-STD-750-1						
		M1038 Method B						
	SSOP	Tj = Tjmax, Iz = 100% of max. datasheet						
# B1b	Steady State Operational	reverse current	1000 hours	44	1920	0		
	TC	JESD22-A104				_		
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	53	2400	0		
		JECD22 4410						
# A3 or	UHAST Unbiased HAST	JESD22-A118 Tamb = 130 °C, RH = 85 %						
+ A3 01	Olibiaseu HAST	· · · · · · · · · · · · · · · · · · ·	-96 hours	53	2400	0		
	•0	JESD22-A102						
# A3 alt	AC Autoclave	Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)						
AS all	Autociave	riessure – 203 kra (23.7 psia)						
	H3TRB	JESD22-A101						
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of						
# A2 alt		rated reverse voltage ^[1]	1000 hours	53	2400	0		
# AZ dit	. cperacare neverse blus	MIL-STD-750 Method 1037	1000 110015	- 55	2400			
	IOL	ton = toff, devices powered to insure ΔT_j =						
# A5	Intermittent Operating Life		1000 hours	53	2400	0		
, ,,,,	2commetene Operating Life	200 0 10. 15000 Cycles	1000 110015	- 55	2400			
	RSH	JESD22-A111						
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	n.a.	n.a.	n.a.		
,, 00	SD		10 3		ma.	mu.		
# C10	Solderability	J-STD-002		37	1110	0		

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Zener	11400	0	0,37	2,68E+09

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